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Front Matter: Volume 10815

, "Front Matter: Volume 10815," Proc. SPIE 10815, Optical Design and Testing VIII, 1081501 (7 November 2018); doi: 10.1117/12.2521302

SPIE.

Event: SPIE/COS Photonics Asia, 2018, Beijing, China

PROCEEDINGS OF SPIE

Optical Design and Testing VIII

Yongtian Wang
Tina E. Kidger
Kimio Tatsuno
Editors

11–13 October 2018
Beijing, China

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Volume 10815

Proceedings of SPIE 0277-786X, V. 10815

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Optical Design and Testing VIII, edited by Yongtian Wang, Tina E. Kidger,
Kimio Tatsuno, Proc. of SPIE Vol. 10815, 1081501 · © 2018 SPIE
CCC code: 0277-786X/18/\$18 · doi: 10.1117/12.2521302

Proc. of SPIE Vol. 10815 1081501-1

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Please use the following format to cite material from these proceedings:

Author(s), "Title of Paper," in *Optical Design and Testing VIII*, edited by Yongtian Wang, Tina E. Kidger, Kimio Tatsumo, Proceedings of SPIE Vol. 10815 (SPIE, Bellingham, WA, 2018) Seven-digit Article CID Number.

ISSN: 0277-786X
ISSN: 1996-756X (electronic)

ISBN: 9781510622289
ISBN: 9781510622296 (electronic)

Published by

SPIE

P.O. Box 10, Bellingham, Washington 98227-0010 USA
Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445

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